## Notice of References Cited Application/Control No. 10/566,011 Examiner Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,212,373	05-1993	Fujioka et al.	235/492
*	В	US-2003/0178483	09-2003	Wakabayashi, Naoyuki	235/380
	С	US-			
	D	US-			
	Ε	US-			
	H-	US-			
	O	US-			
	Ι	US-			
		US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Φ					
	ø					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

	HON-I ATENI DOCUMENTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U	RFID standard by Steve Halliday,pub.January 31, 2002						
	٧							
	w							
	×							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classif ications may be US or foreign.